

**Notice of References Cited**

Application/Control No.

09/495,971

Applicant(s)/Patent Under

Reexamination  
NETER, SARIT

Examiner

Timothy J Henn

Art Unit

2612

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,176,373	11-1979	Dillon et al.	348/253
*	B	US-5,329,312	07-1994	Boisvert et al.	348/256
	C	US-3,971,065 ✓	07-1976	Bayer, Bryce E.	348/276
*	D	US-5,541,654	07-1996	Roberts, Peter C. T.	348/301
	E	US-5,790,191 ✓	08-1998	Zhang, Tao	348/300
	F	US-6,141,049 ✓	10-2000	Harada, Kouichi	348/296
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Frame-transfer CMOS active pixel sensor with pixel binning Zhimin Zhou; Pain, B.; Fossum, E.R.; Electron Devices, IEEE Transactions on , Volume: 44 , Issue: 10 , Oct. 1997 □□Pages: 1764 - 1768
*	V	Submicron spaced lens array process technology for a high photosensitivity CCD image sensor Sano, Y. et al. Electron Devices Meeting, 1990. Technical Digest., International , 9-12 Dec. 1990
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.